



Contribution ID: 6

Type: **Oral presentation**

XDBL1 diagnostic beamline

Tuesday 13 May 2025 14:30 (30 minutes)

Three dedicated beamlines for accelerator diagnostics are under discussion for Elettra 2.0. Two of them will be dedicated to measuring the transverse dimensions of the beam, using the X-ray pinhole camera technique with bending magnets as the source. A third line could transport visible-near UV radiation to a streak camera for the analysis of the longitudinal profile of the beam.

In this presentation we provide a general description of the first beamline to be constructed (XDBL1), dedicated to the measurement of the beam size from a non-dispersive source and aimed at the measurement of the beam emittance.

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Session Classification: Session 7